Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/740,033	CERNY ET AL.	
Examiner	Art Unit	
Phallaka Kik	2825	

SEARCHED					
Class	Subclass	Date	Examiner		
716	5,3,18	2/1/2006	PK		
703	16, 17	2/1/2006	PK		
714	741,33	2/1/2006	PK		
324	750	2/1/2006	PK		
			-		
			-		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
716	5,3,18	2/2/2006	PK		
703	16	2/2/2006	PK		
-USP (see at		2/2/2006	PK		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
BRS (EAST)USPAT, USPGPUB Cls/sub searched: 716/1-18; 703/2,13-22; 714/32- 57,733,734,741; 324/537-769 (see attached)	2/1/2006	PK		
EPO, JPO, IBM TDB, Derwent (see attached)	2/1/2006	PK		
IEE/IEEE Xplore (see attached)	2/1/2006	PK		
Consulted with Examiner Vuthe Siek allowable subject matter	2/2/2006	РК		
Consulted with Examiner James C. Kerveros suggested search in 714/741,33; 324/750but no cross-referencing.	2/3/2006	PK		